	Application No.	Applicant(s)		
Notice of Allowability	10/602,827	TSUNODA, ATSUO	SUNODA, ATSUO	
	Examiner	Art Unit		
	Tuan N. Nguyen	2828		
The MAILING DATE of this communication apper All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this app or other appropriate communication GHTS. This application is subject to	olication. If not include will be mailed in due	ed course. THIS	
1. This communication is responsive to <u>7/25/2005</u> .				
2. The allowed claim(s) is/are 2-5.			•	
 Acknowledgment is made of a claim for foreign priority un a)	der 35 U.S.C. § 119(a)-(d) or (f).			
 Certified copies of the priority documents have 				
2. Certified copies of the priority documents have	• • • • • • • • • • • • • • • • • • • •			
3. Copies of the certified copies of the priority doc	cuments have been received in this r	national stage applicat	tion from the	
International Bureau (PCT Rule 17.2(a)).				
* Certified copies not received:				
Applicant has THREE MONTHS FROM THE "MAILING DATE" of noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		complying with the rec	_l uirements	
4. A SUBSTITUTE OATH OR DECLARATION must be submit INFORMAL PATENT APPLICATION (PTO-152) which give			OTICE OF	
5. CORRECTED DRAWINGS (as "replacement sheets") mus	t be submitted.			
(a) \square including changes required by the Notice of Draftspers	on's Patent Drawing Review (PTO-9	948) attached		
1) 🗌 hereto or 2) 🔲 to Paper No./Mail Date		•		
(b) ☐ including changes required by the attached Examiner's Paper No./Mail Date	Amendment / Comment or in the O	ffice action of		
Identifying indicia such as the application number (see 37 CFR 1. each sheet. Replacement sheet(s) should be labeled as such in the			back) of	
6. DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.				
	·			
Attachment(s) 1. ☐ Notice of References Cited (PTO-892)	5. Notice of Informal Pa	atent Application (PTC	1.152)	
2. Notice of Draftperson's Patent Drawing Review (PTO-948)	6. ☑ Interview Summary (• • • • • • • • • • • • • • • • • • • •	7-102)	
	Paper No./Mail Date	Paper No./Mail Date <u>9/15/2005</u> .		
 Information Disclosure Statements (PTO-1449 or PTO/SB/06 Paper No./Mail Date	8), 7. 🛛 Examiner's Amendm	7. 🛮 Examiner's Amendment/Comment		
	8. 🛭 Examiner's Stateme	8. Examiner's Statement of Reasons for Allowance		
or Brondyna.	9. Other			

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Response to Amendment

1. In responding to applicant's response filed 07/25/2005 claims 2-4 have been amended, and claim 1 has been canceled. Telephone interviewed on 09/15/2005 – claim 5 has been amended, and claim 6 has been canceled.

EXAMINER'S AMENDMENT

2. An examiner's amendment to the record appears below, to the amended claim 5 should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no latter than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview on September 15, 2005 with Ms. Deborah Gladstein (Attorney for Applicant, Reg. No. 43,636).

Claim5:

5 (Currently amended). A semiconductor laser device manufacturing method comprising the steps of:

forming at least an active layer, a first clad layer, a second clad layer and upper layers including a cap layer on a substrate; and

forming a ridge section comprised of the second clad layer and the upper layers by subjecting the second clad layer and the upper layers to dry etching and subsequently to wet etching, the upper layers protruding in both widthwise directions beyond the second clad layer providing a step of not smaller than 0.13 µm between the upper layers and the second clad layer; and

forming a current constriction layer provided on both sides of the ridge section, and a portion of the current constriction layer, the portion being located outside a portion brought in contact with the ridge section and having surfaces formed flatly, is formed to have a thickness smaller than a thickness of the second clad layer of the ridge section.

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Claim 6 is CANCELED.

REASON FOR ALLOWANCE

Allowable Subject Matter

3. The following is an examiner's statement of reasons for allowance, with respect to claims

1, and 5 the references of the record fail to teach or suggest the semiconductor device and

method of making:

Claims 1, 5:

A semiconductor with an active layer, a first clad on a substrate and a ridge section

constructed of a second clad layer and upper layers including a cap layer on first clad

layer, where the upper layer protruding in both widthwise directions beyond the second

clad layer, providing a step not smaller than 0.13um between the upper layers and the

second clad layer, wherein the constriction layer is located on both sides of he ridge,

while a portion of the constriction layer is located outside a portion brought in contact

with the ridge section having surfaces formed flatly with thickness smaller than the

thickness of second clad layer of the ridge section.

4. Any comments considered necessary by applicant must be submitted no later than the

payment of the issue fee and, to avoid processing delays, should preferably accompany the issue

fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for

Allowance."

Communication Information

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Any inquiry concerning this communication or earlier communications from the examiner should be directed to Tuan N Nguyen whose telephone number is (571) 272-1948. The examiner can normally be reached on M-F: 7:30 - 4:30PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Harvey Minsun can be reached on (571) 272-1835. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Tuan N. Nguyen

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